

# PC354NT

**Mini-flat Package,  
AC Input Type Photocoupler**

## ■ Features

1. AC inputs
2. Opaque type, mini-flat package

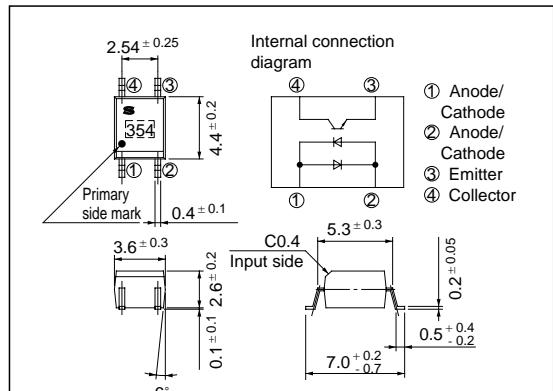
**PC354NT** (1-channel)

3. Subminiature type  
(The volume is smaller than that of our conventional DIP type by as far as 30 %.)
4. Isolation voltage between input and output

**PC354NT••V<sub>iso</sub>** : 3 750V<sub>rms</sub>

## ■ Outline Dimensions

(Unit : mm)



## ■ Applications

1. Hybrid substrates that require high density mounting.
2. Programmable controllers

## ■ Absolute Maximum Ratings

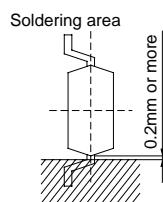
(Ta = 25°C)

Parameter		Symbol	Rating	Unit
Input	Forward current	I <sub>F</sub>	± 50	mA
	* <sup>1</sup> Peak forward current	I <sub>FM</sub>	± 1	A
	Power dissipation	P	70	mW
Output	Collector-emitter voltage	V <sub>CEO</sub>	35	V
	Emitter-collector voltage	V <sub>ECO</sub>	6	V
	Collector current	I <sub>C</sub>	50	mA
	Collector power dissipation	P <sub>C</sub>	150	mW
Total power dissipation		P <sub>tot</sub>	170	mW
* <sup>2</sup> Isolation voltage		V <sub>iso</sub>	3 750	V <sub>rms</sub>
Operating temperature		T <sub>opr</sub>	- 30 to + 100	°C
Storage temperature		T <sub>stg</sub>	- 40 to + 125	°C
* <sup>3</sup> Soldering temperature		T <sub>sol</sub>	260	°C

\*1 Pulse width &lt;=100μ s, Duty ratio : 0.001

\*2 40 to 60% RH, AC for 1 minute

\*3 For 10 seconds



Classification of current transfer ratio (CTR)

Model No.	Rank mark	CTR (%)
PC354N1T	A	50 to 150
PC354NT	A or No mark	20 to 400

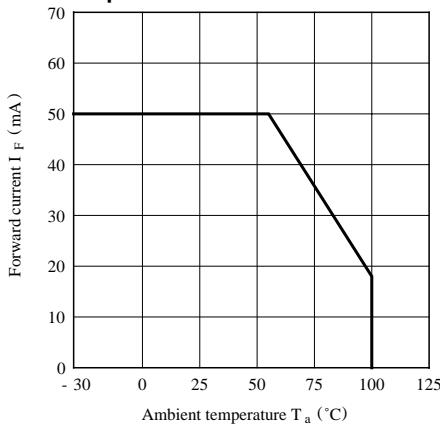
※ Conditions : I<sub>F</sub> = ± 1mA, V<sub>CE</sub> = 5V, Ta = 25°C

## ■ Electro-optical Characteristics

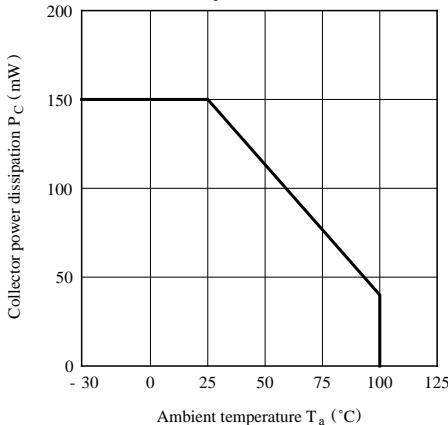
(Ta = 25°C)

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit	
Input	Forward voltage	V <sub>F</sub>	I <sub>F</sub> = ± 20mA	-	1.2	1.4	V	
	Terminal capacitance	C <sub>t</sub>	V = 0, f = 1kHz	-	30	250	pF	
Output	Collector dark current	I <sub>CEO</sub>	V <sub>CE</sub> = 20V, I <sub>F</sub> = 0	-	-	10 <sup>-7</sup>	A	
	Collector-emitter breakdown voltage	BV <sub>CEO</sub>	I <sub>C</sub> = 0.1mA, I <sub>F</sub> = 0	35	-	-	V	
Transfer-characteristics	Emitter-collector breakdown voltage	BV <sub>ECO</sub>	I <sub>E</sub> = 10 μA, I <sub>F</sub> = 0	6	-	-	V	
	Current transfer ratio	CTR	I <sub>F</sub> = ± 1mA, V <sub>CE</sub> = 5V	20	-	400	%	
	Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	I <sub>F</sub> = ± 20mA, I <sub>C</sub> = 1mA	-	0.1	0.2	V	
	Isolation resistance	R <sub>ISO</sub>	DC500V, 40 to 60% RH	5 x 10 <sup>10</sup>	10 <sup>11</sup>	-	Ω	
	Floating capacitance	C <sub>f</sub>	V = 0, f = 1MHz	-	0.6	1.0	pF	
	Response time	Rise time	t <sub>r</sub>	V <sub>CE</sub> = 2V, I <sub>C</sub> = 2mA	-	4	18	μs
		Fall time	t <sub>f</sub>	R <sub>L</sub> = 100Ω	-	3	18	μs

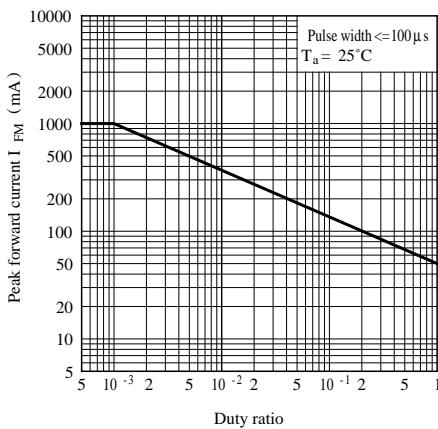
**Fig. 1 Forward Current vs. Ambient Temperature**



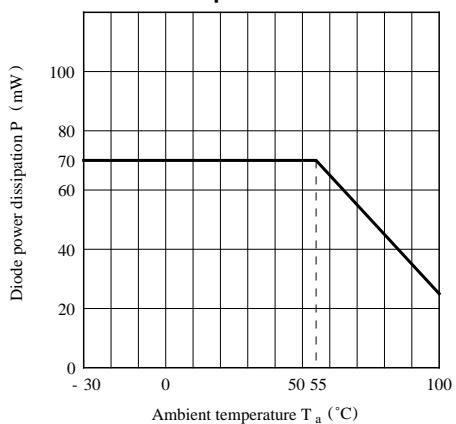
**Fig. 3 Collector Power Dissipation vs. Ambient Temperature**



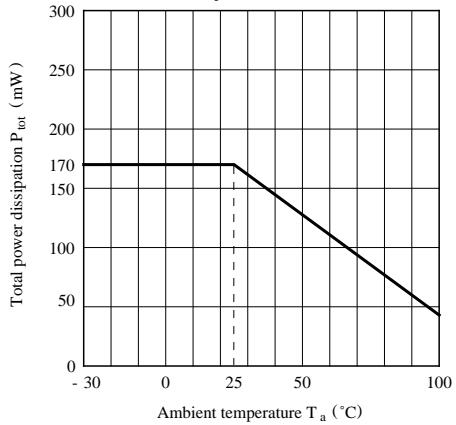
**Fig. 5 Peak Forward Current vs. Duty Ratio**



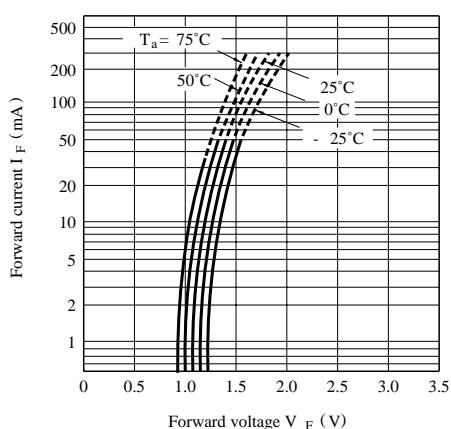
**Fig. 2 Diode Power Dissipation vs. Ambient Temperature**



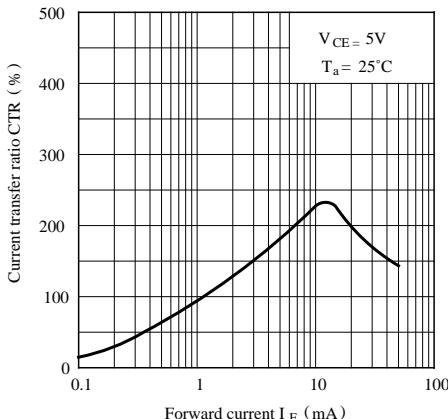
**Fig. 4 Total Power Dissipation vs. Ambient Temperature**



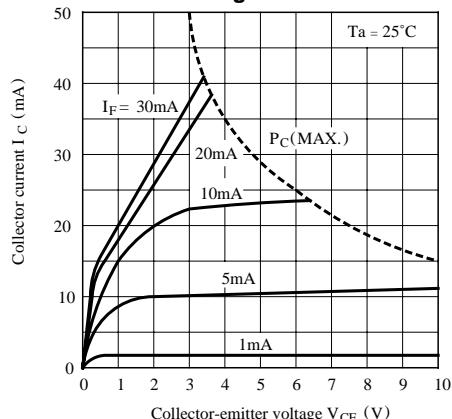
**Fig. 6 Forward Current vs. Forward Voltage**



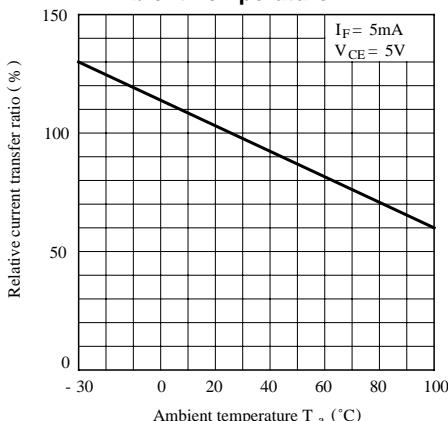
**Fig. 7 Current Transfer Ratio vs. Forward Current**



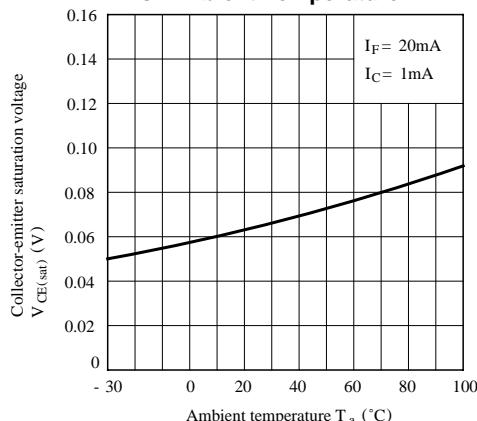
**Fig. 8 Collector Current vs. Collector-emitter Voltage**



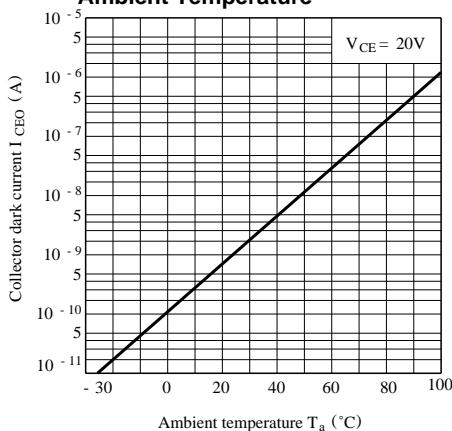
**Fig. 9 Relative Current Transfer Ratio vs. Ambient Temperature**



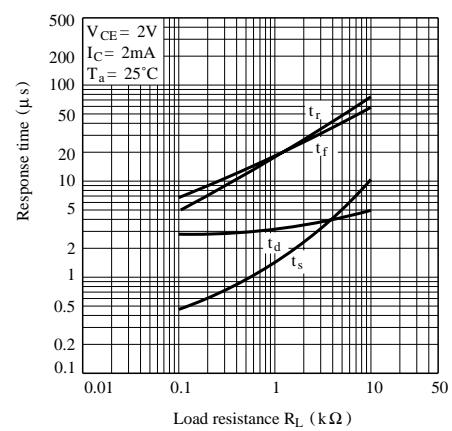
**Fig. 10 Collector-emitter Saturation Voltage vs. Ambient Temperature**



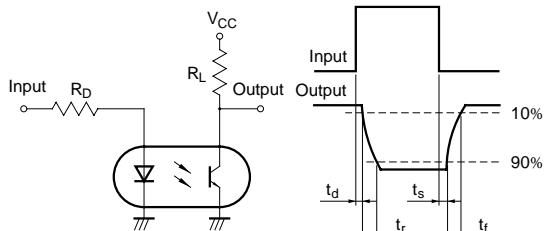
**Fig.11 Collector Dark Current vs. Ambient Temperature**



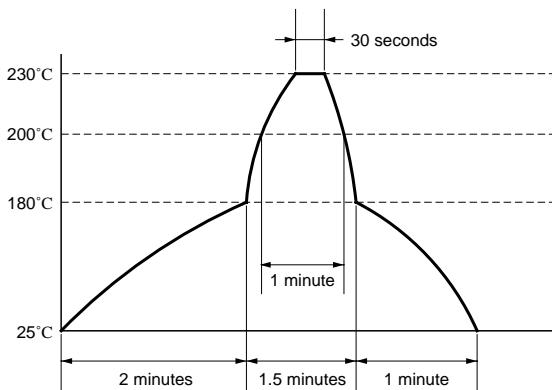
**Fig.12 Response Time vs. Load Resistance**



### Test Circuit For Response Time

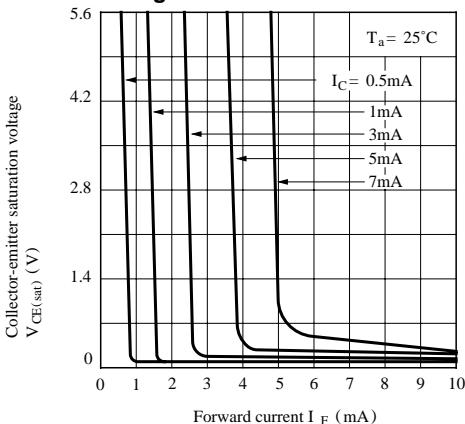


### ■ Temperature Profile of Soldering Reflow



- Please refer to the chapter “Precautions for Use”.

**Fig.13 Collector-emitter Saturation Voltage vs. Forward Current**



- (1) One time soldering reflow is recommended within the condition of temperature and time profile shown below.
- (2) When using another soldering method such as infrared ray lamp, the temperature may rise partially in the mold of the device. Keep the temperature on the package of the device within the condition of above (1).